



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of: Richard William CHARM et al. Confirmation No: 6496
Serial No.: 10/689,657 Art Unit: To be Assigned
Filed: October 22, 2003 Examiner: To be Assigned
For: PROCESS FOR THE USE OF BIS-CHOLINE AND TRIS-CHOLINE IN THE
CLEANING OF QUARTZ-COATED
POLYSILICON AND OTHER MATERIALS Atty Docket No: 060937-0139-US

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

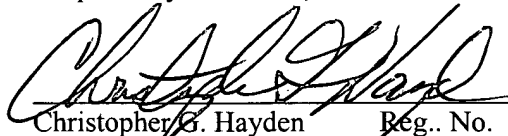
Sir:

Pursuant to applicants' duty of disclosure under 37C.F.R. 1.56, attached is a PTO-1449 citing the thirty-nine (39) references noted in the application for the Examiner's consideration. Copies of the foreign references are enclosed for the Office's convenience (U.S. references are not submitted herewith as this application was filed after June 1, 2003).

No additional fees are believed due, however, should it be deemed fees or credits are due in this matter, the Examiner is authorized to charge/credit Morgan, Lewis & Bockius LLP Deposit Account No. 50-0310.

Respectfully submitted,

Date: March 2, 2004


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(202) 739-3000

LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				ATTY DOCKET NO.		APPLICATION NO	
				060937-0139		10/689,657	
				APPLICANT Richard William CHARM et al.			
				FILING DATE		GROUP	
				October 22, 2003		To be Assigned	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A01						
	A02						

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	B01	64-42653	01/1989	Japan				
	B02	64-81949	03/1989	Japan				
	B03	62-2813232	12/1987	Japan				
	B04	63-208043	08/1988	Japan				
	B05	11-197523	07/1999	Japan				
	B06	8-87118	04/1996	Japan				
	B07	6-163495	06/1994	Japan				
	B08	6-41773	02/1994	Japan				
	B09	5-181753	07/1993	Japan				
	B10	4-124668	04/1992	Japan				
	B11	4-350660	12/1992	Japan				
	B12	3-227009	10/1991	Japan				
	B13	2-275631	11/1990	Japan				
	B14	1-191450	08/1989	Japan				
	B15							
	B16							
	B17							

OTHER REFERENCES <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>		
	C01	

EXAMINER	DATE CONSIDERED
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A01	4,403,028	09/1983	Ward, Jr. et al.			
	A02	4,172,005	10/1979	Muraoka et al.			
	A03	4,239,661	12/1980	Muraoka et al.			
	A04	4,294,911	10/1981	Guild			
	A05	4,339,340	07/1982	Muroaka et al.			
	A06	4,395,479	07/1983	Ward et al.			
	A07	4,401,747	08/1983	Ward, Jr. et al.			
	A08	4,428,871	01/1984	Ward et al.			
	A09	4,464,461	08/1984	Guild			
	A10	4,617,251	10/1986	Sizensky			
	A11	4,744,834	05/1988	Haq			
	A12	4,770,713	09/1988	Ward			
	A13	4,824,763	04/1989	Lee			
	A14	4,904,571	02/1990	Miyashita et al.			
	A15	5,102,777	04/1992	Lin et al.			
	A16	5,779,791	01/1994	Aldrich et al.			
	A17	5,308,745	05/1994	Schwartzkopf			
	A18	5,334,332	08/1994	Lee			
	A19	5,399,464	03/1995	Lee			
	A20	5,417,802	05/1995	Obeng			
	A21	5,480,585	01/1996	Shiotsu et al.			
	A22	5,635,423	06/1997	Huang et al.			
	A23	5,705,430	01/1998	Avanino et al.			
	A24	5,739,579	04/1998	Chiang et al.			
	A25	5,846,695	12/1998	Iwata et al.			
	A26						
	A27						

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